

<b>Notice of References Cited</b>	Application/Control No. 10/071,280	Applicant(s)/Patent Under Reexamination CHA, CHANG YUL	
	Examiner Edna Wong	Art Unit 1753	Page 1 of 1

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	M	US-			

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# **Notice of References Cited**

Application/Control No.  
10/071,280

Applicant(s)/Patent Under  
Reexamination  
CHA, CHANG YUL

Examiner

Edna Wong

02/17/04

Art Unit

1753

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